

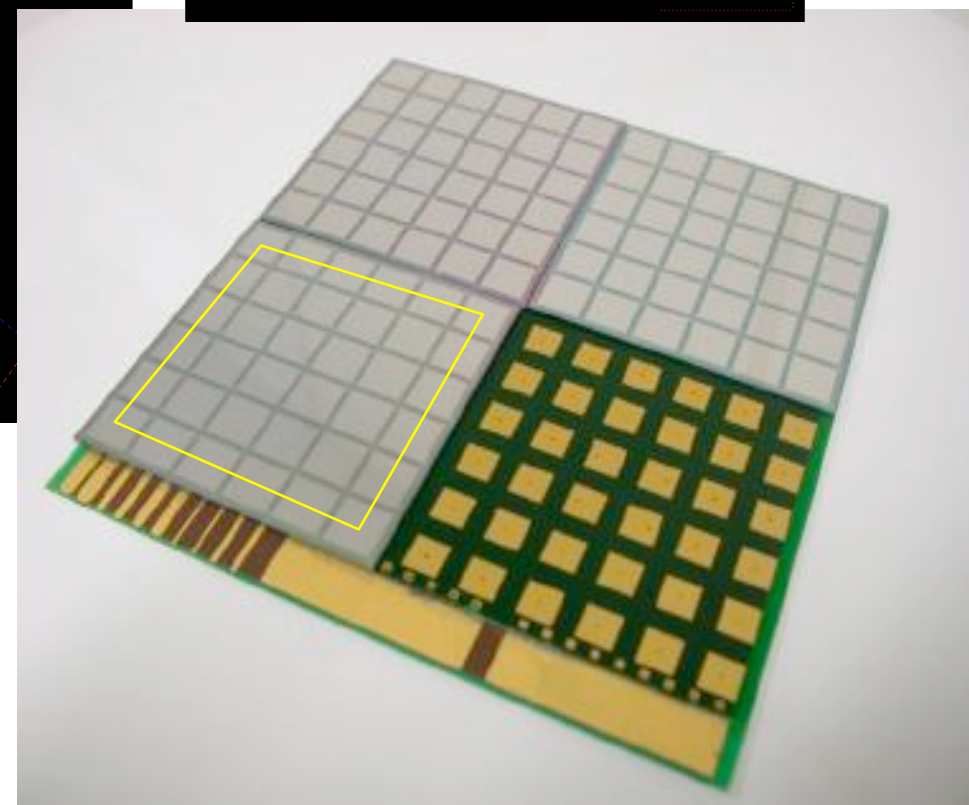
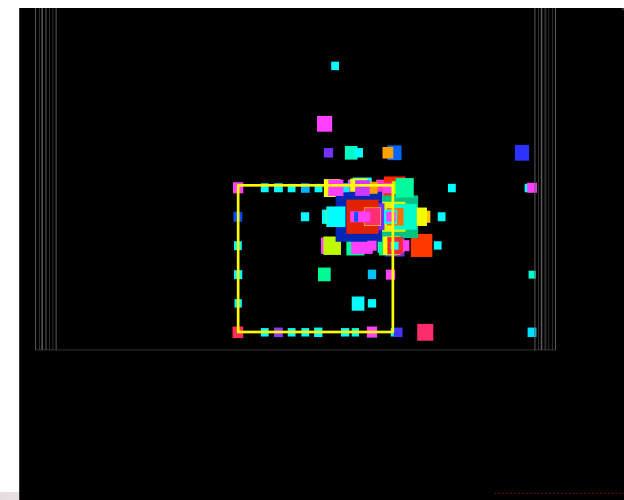
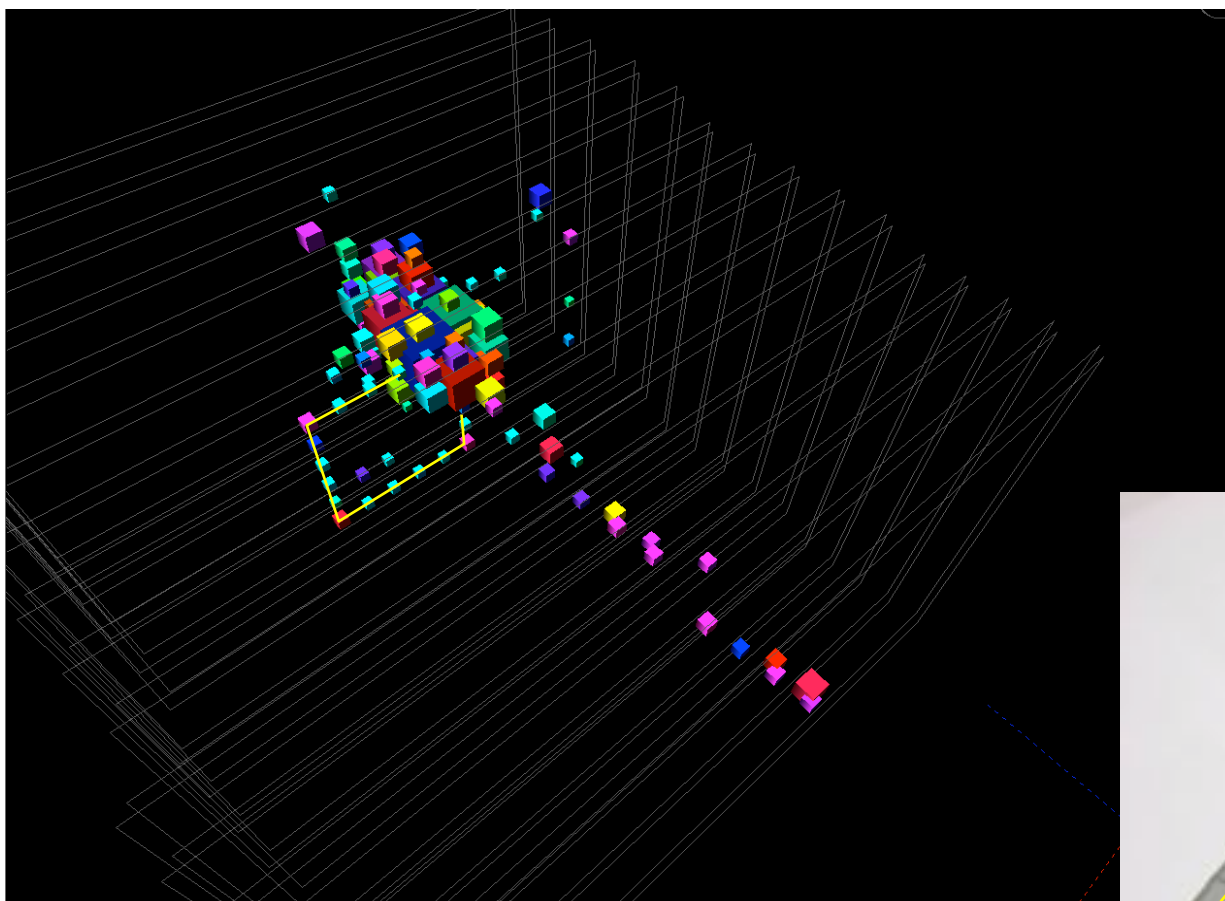
Study of guard-ring design for Si-W wafer

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François Morisseau & Jean-Charles Vanel





Introduction

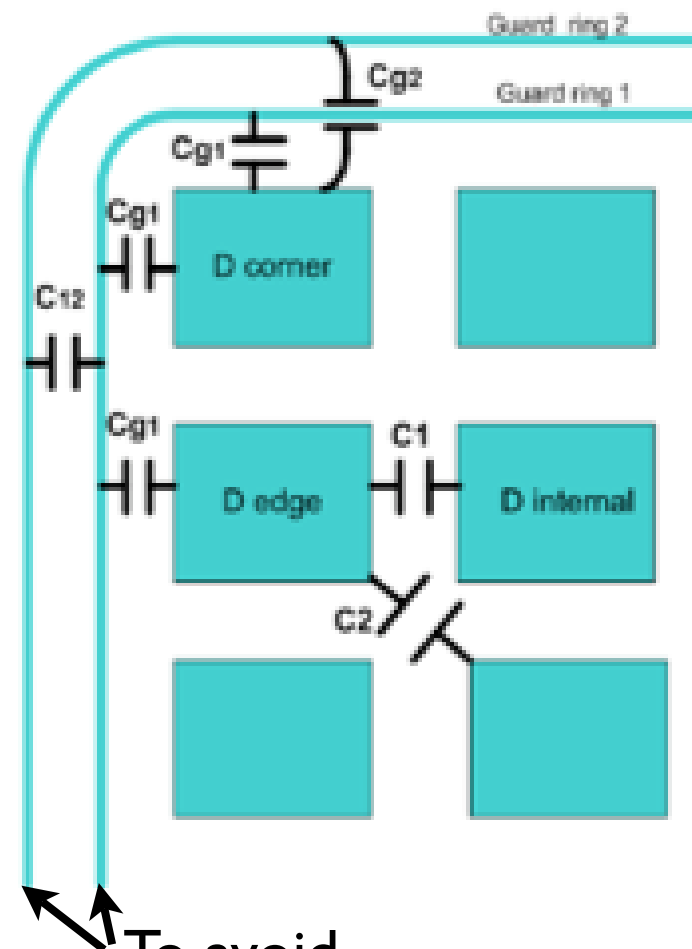
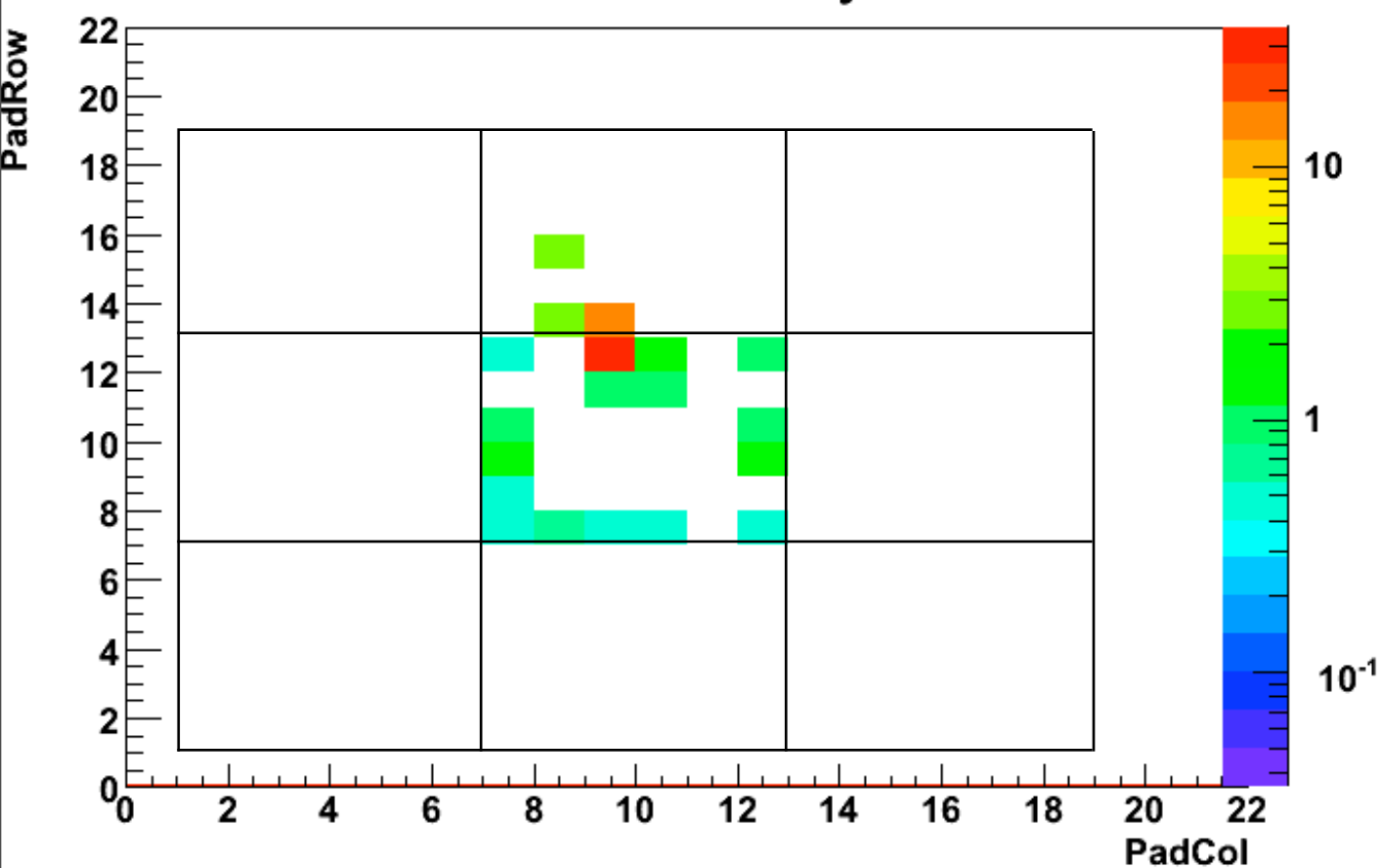


Square Events



Hypothesis

Run 300378 30 GeV Evt 7366 Layer 6



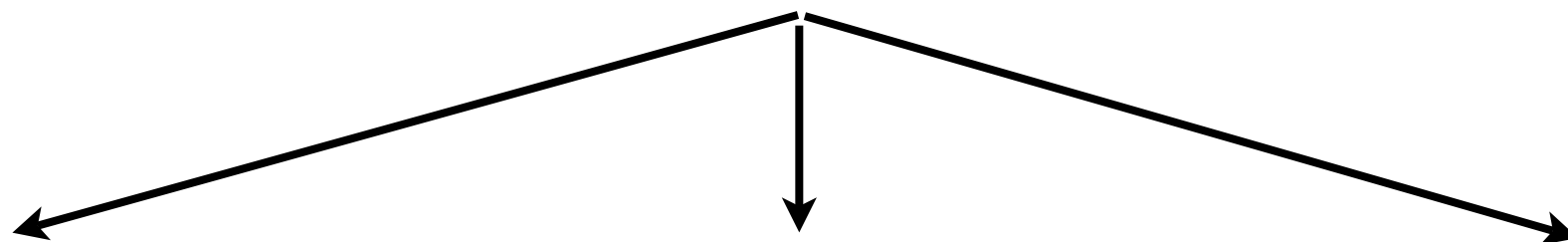
Crosstalk

capacitance effect between guard-rings and wafer border pads.



Study Overview

Aim:
test the previous hypothesis and evaluate different guard-ring options



Test beam analysis

- importance of the effect
- finding pertinent variables

Test bench

- ① validate the measurement method with a Cu-Epoxy scale model. (pure crosstalk effect study)
- ② characterise real 3x3 wafers

Simulations with SILVACO package

- capacitances
- charge injections



Outline

- **Set up**

- Cu-Epoxy scale model
- General description
- 2 measurement protocols

- **Measurements**

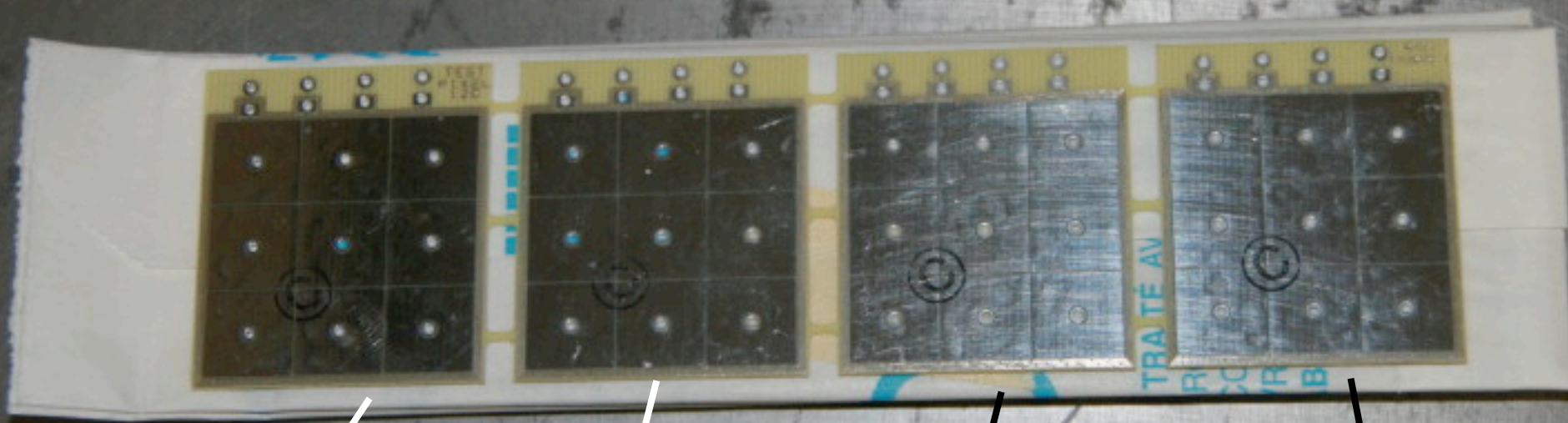
- First results
- Geometrical crosstalk distributions
- Impact of guard-ring positions

- **Conclusion**



Cu - Epoxy

4 guard-ring options (4 layers each)



4 continuous

4 segmented
1 cm

4 segmented
3 mm

2 segmented 1 cm
2 continuous

General Set up

Cu-Epoxy

Binocular

Sin. wave generator

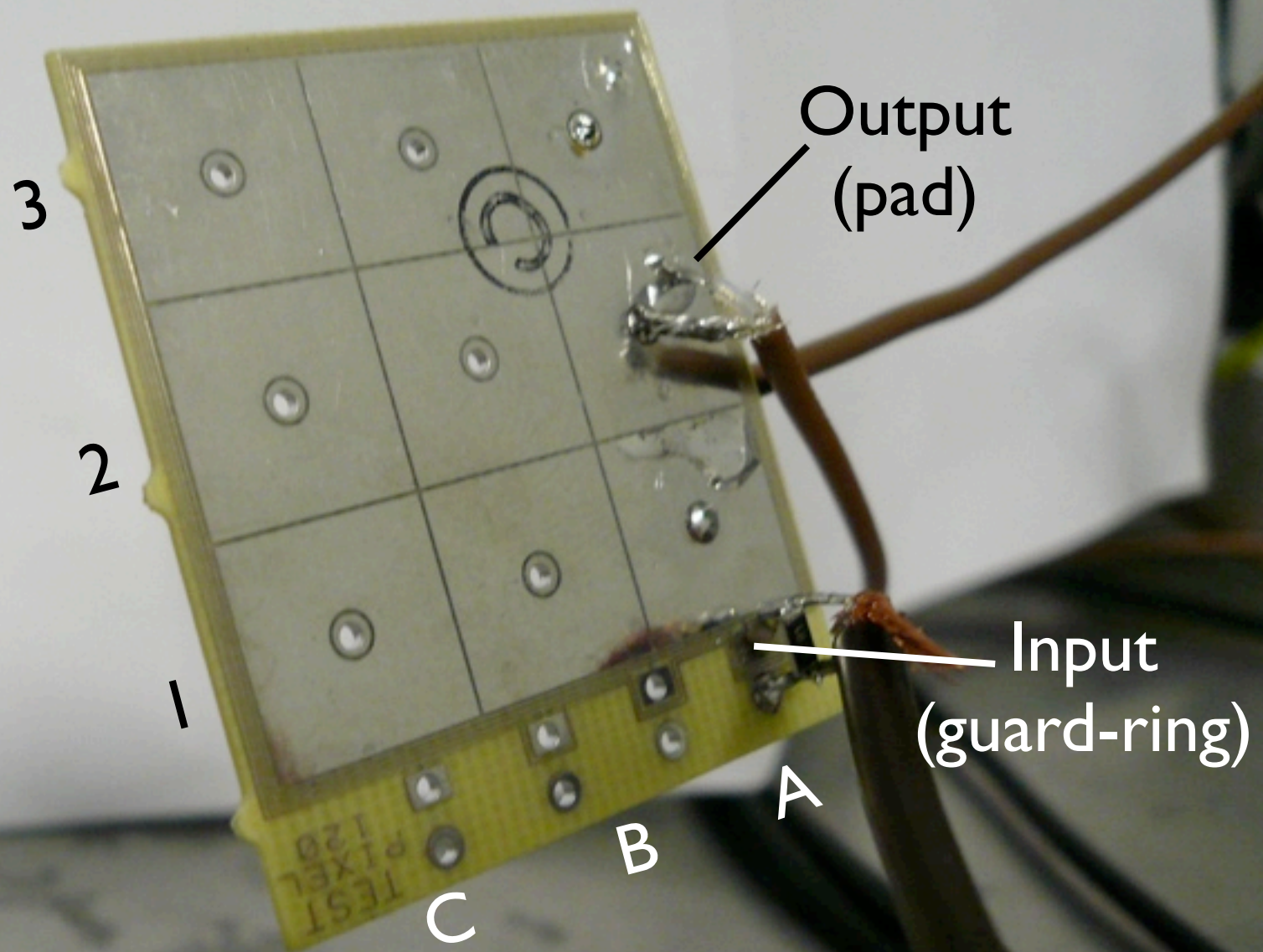
250 00.1 250 00.1

Power supply
(for the elec. card)

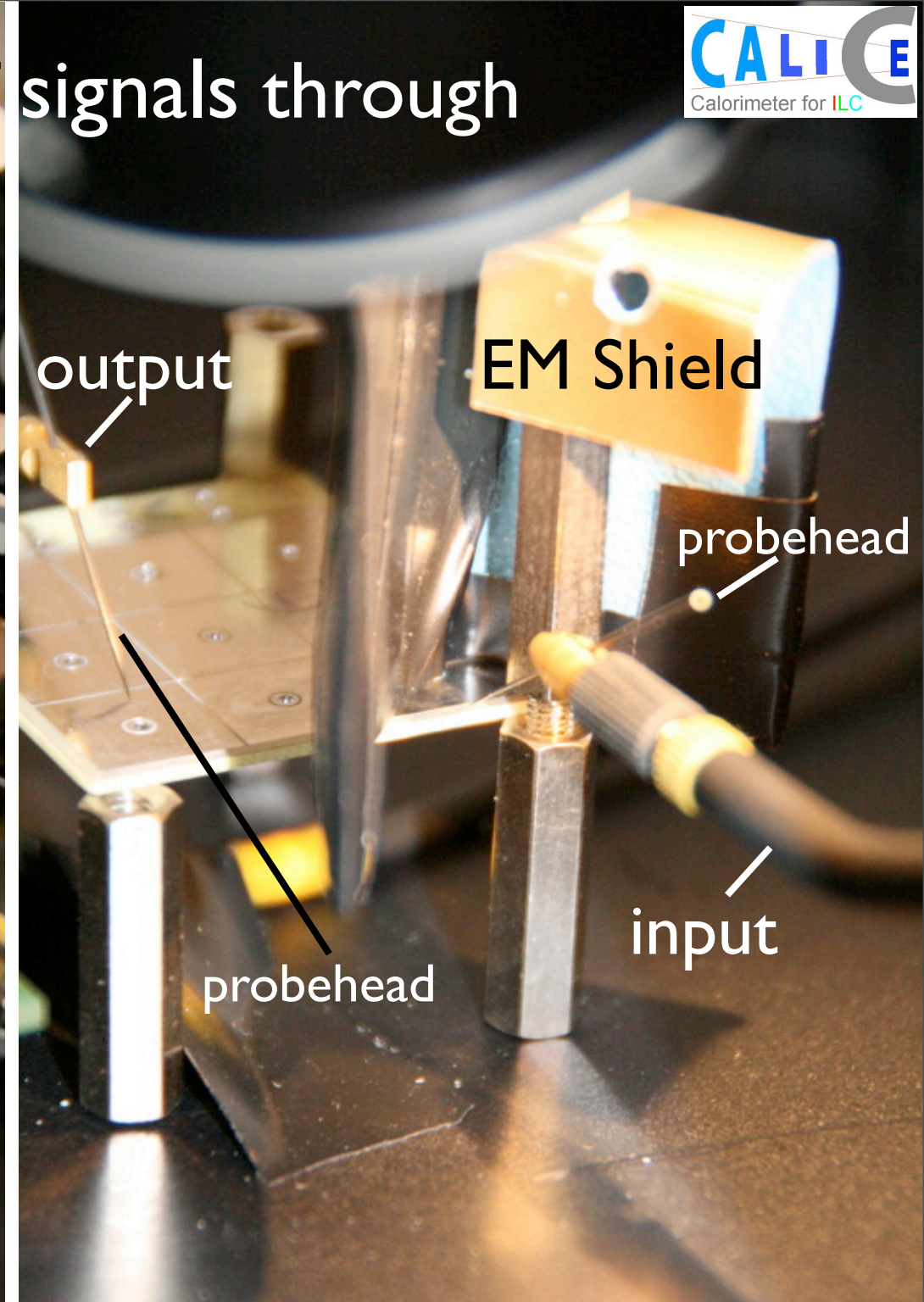
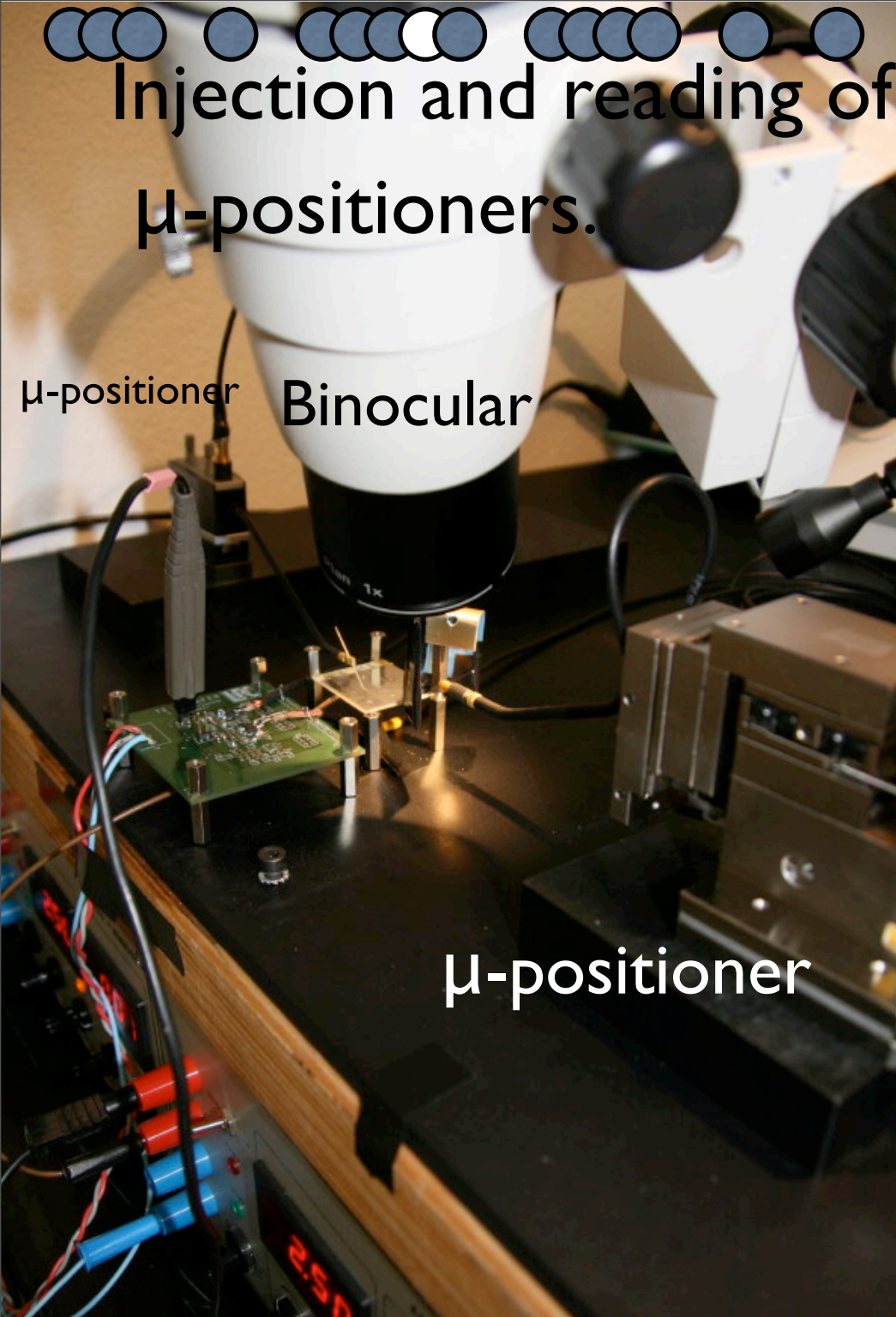
@LPC Clermont



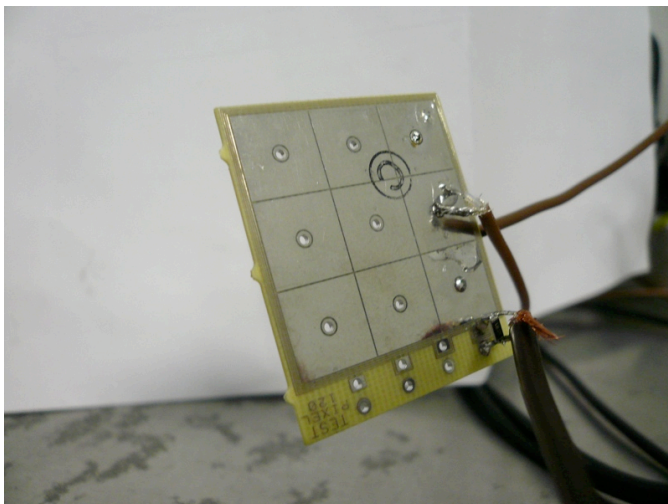
Injection and reading of signals through solder bonds



Injection and reading of signals through μ -positioners.

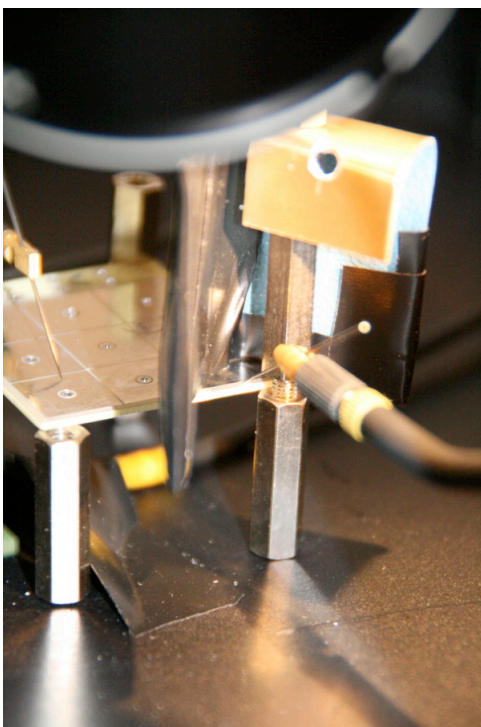


Advantages and Drawbacks



+ best electrical connections

- difficult to change the input or/and output position



+ easy to change the input or/and output position

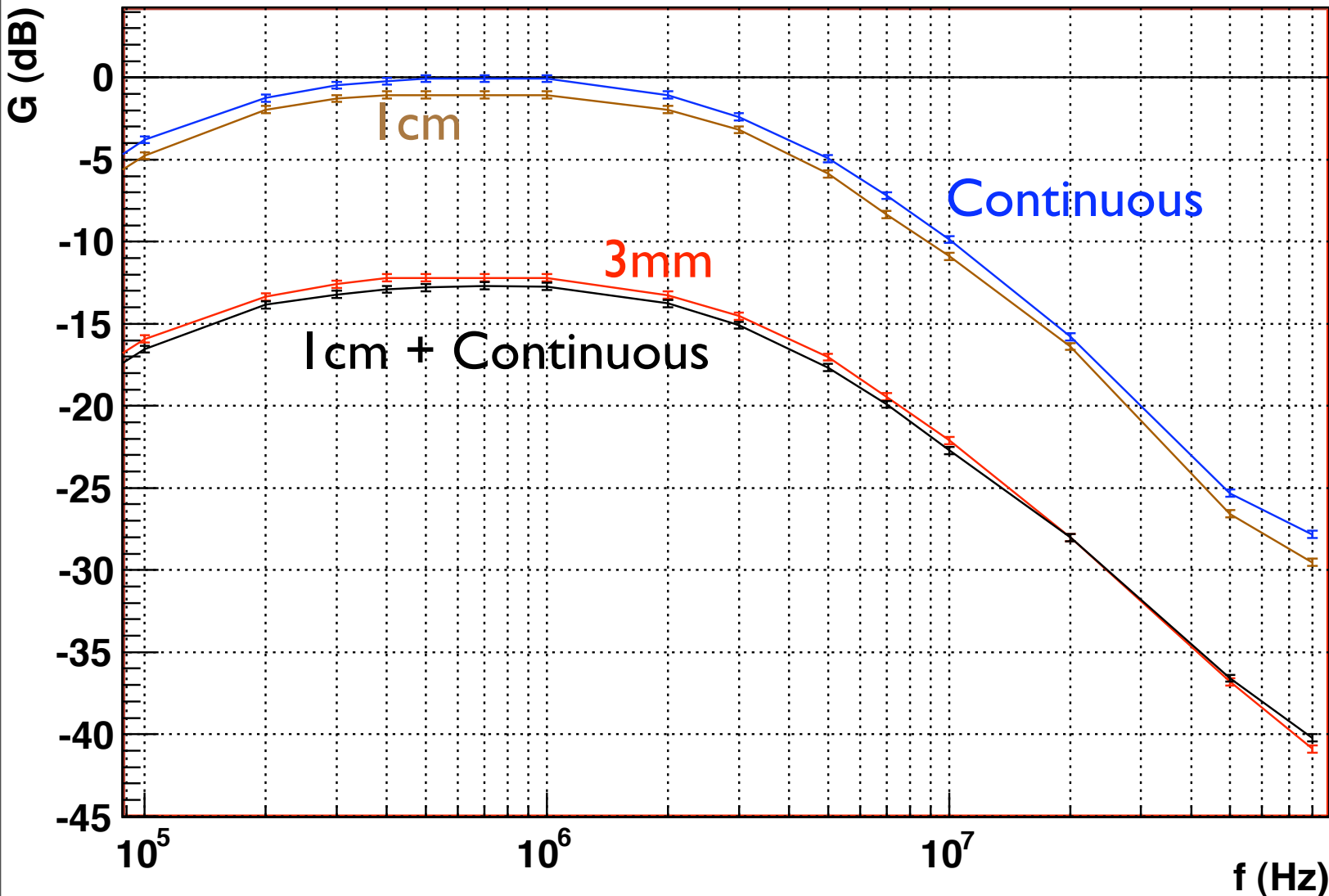
+ same as for real wafers

- EM radiations

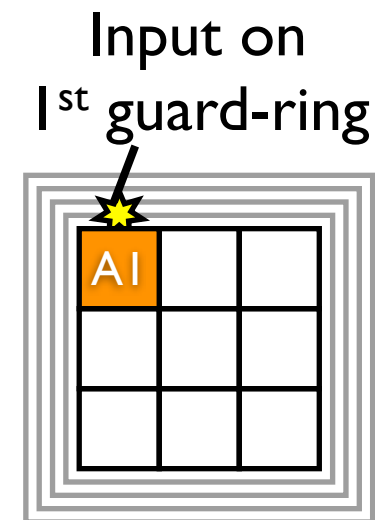
- electrical connections not as good as they are with solder bonds



First results

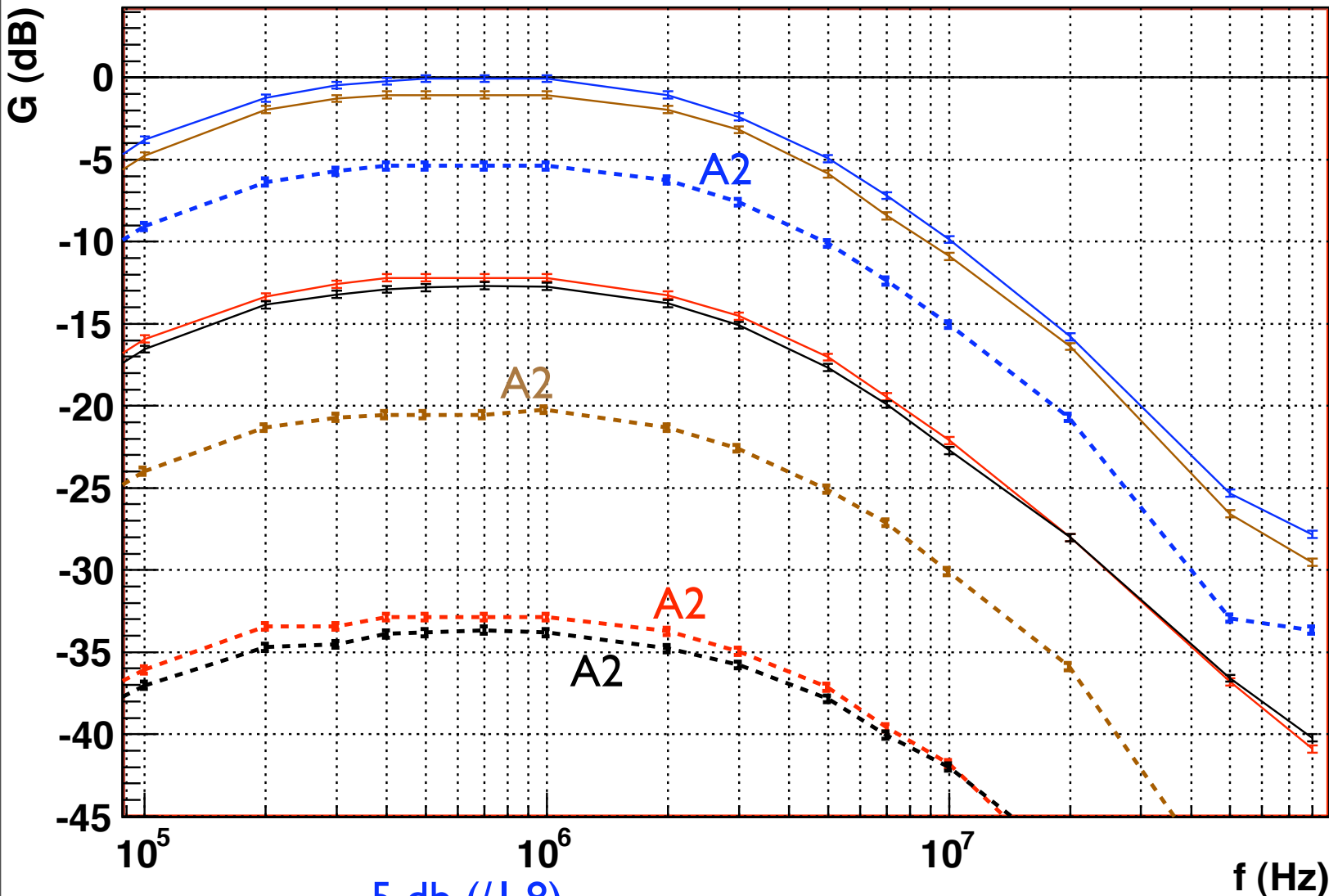


solder bonds





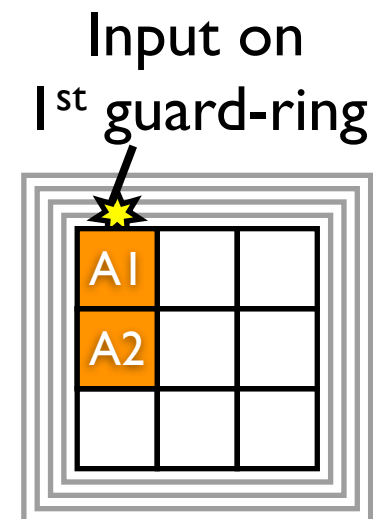
First results



A1 → A2

- 5 db (/1.8)
- 20 db (/10)
- 20 db (/10)
- 20 db (/10)

solder bonds



Continuous

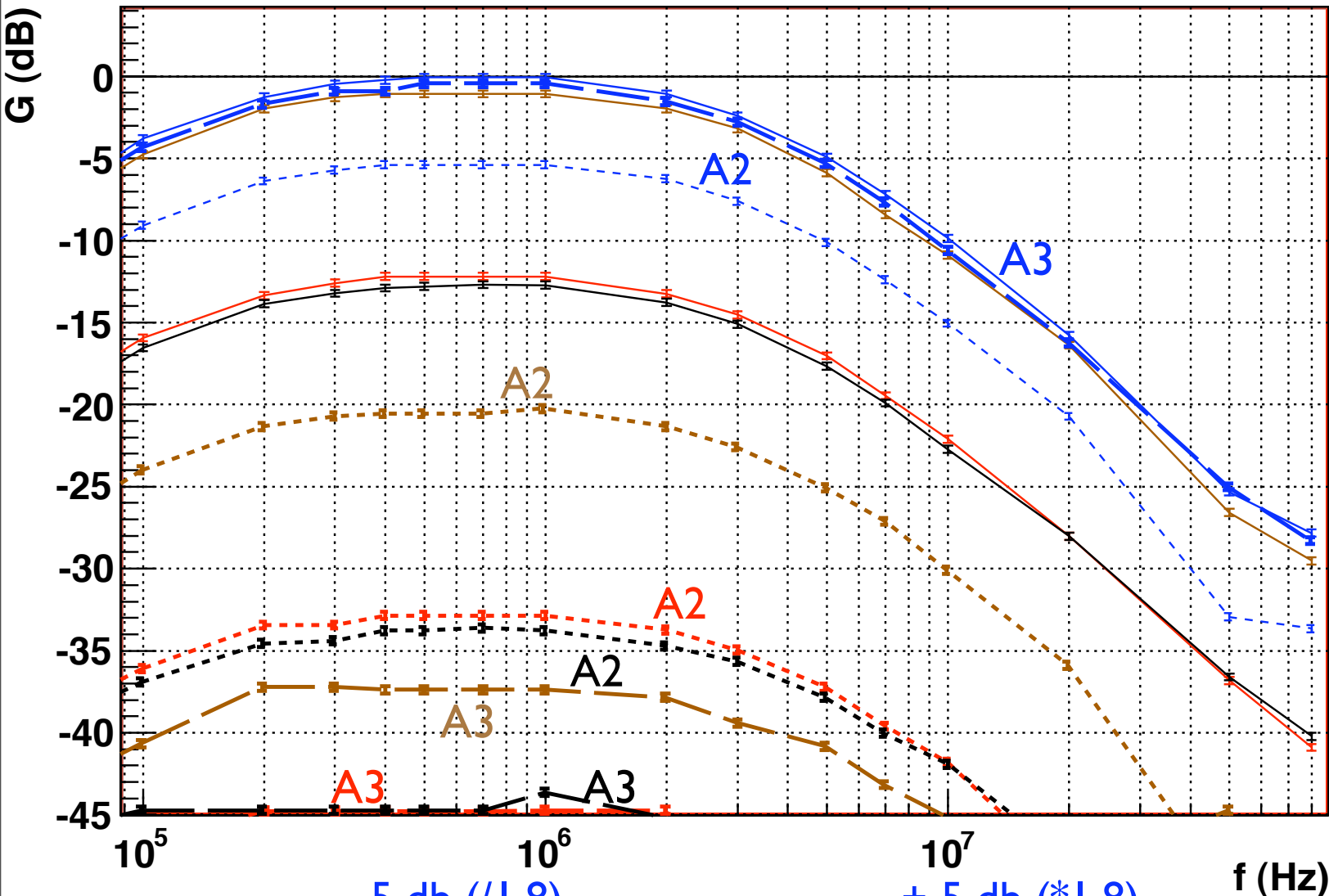
1cm

3mm

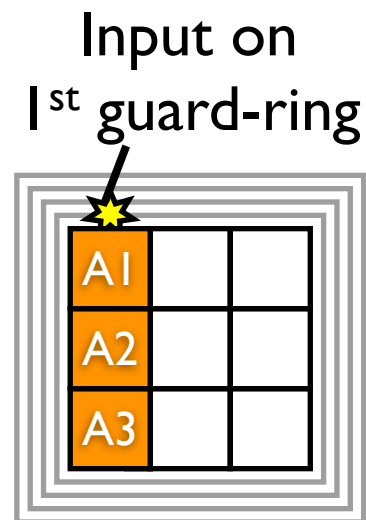
1cm + Continuous



First results



solder bonds



A1 → A2

- 5 db (/1.8)
-20 db (/10)
-20 db (/10)
-20 db (/10)

A2 → A3

+ 5 db (*1.8)
-18 db (/8)
<-10 db (/X , X>3)
<-10 db (/X , X>3)

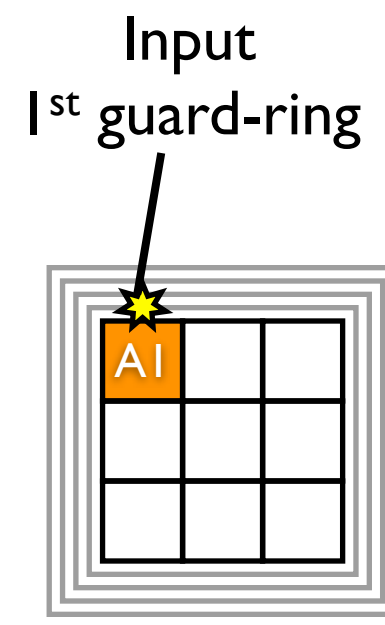
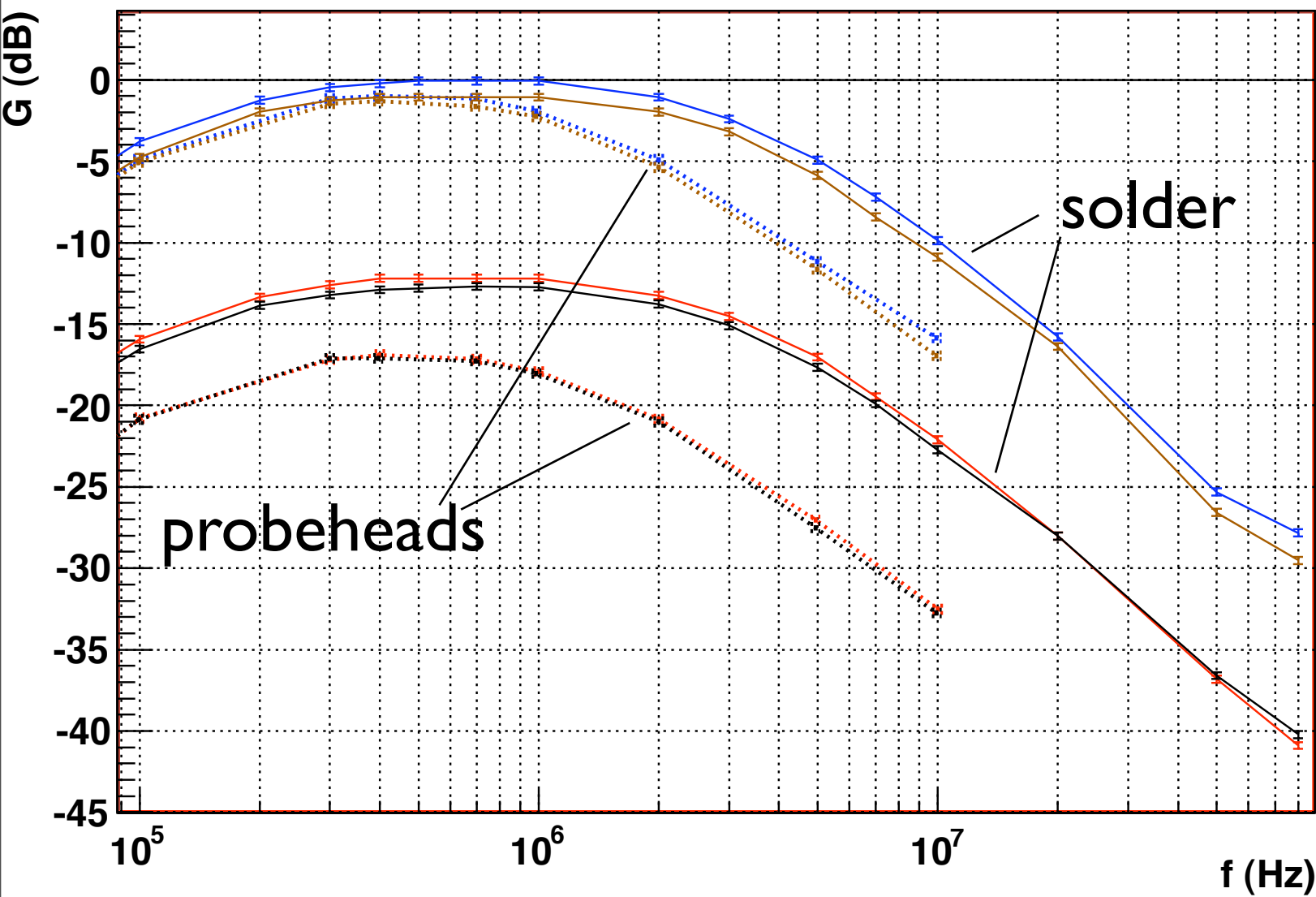
Continuous

1cm

3mm

1cm + Continuous

Comparison between the two measurement protocols

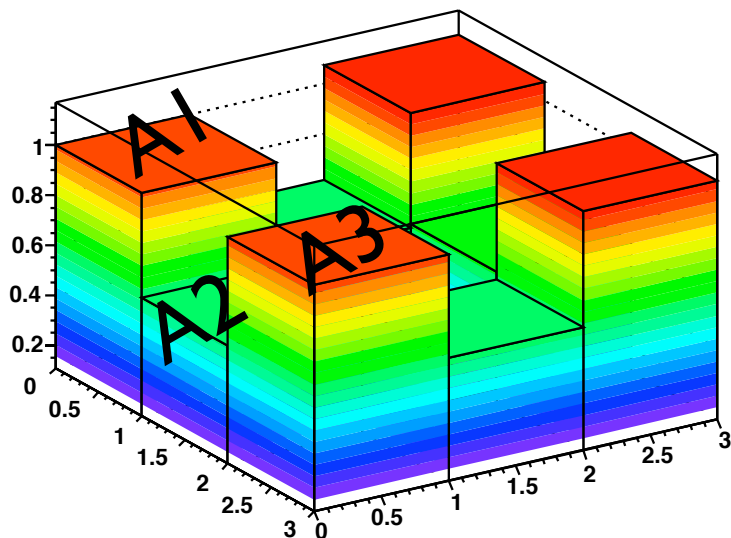


Continuous
 1cm
 3mm
 1cm + Continuous

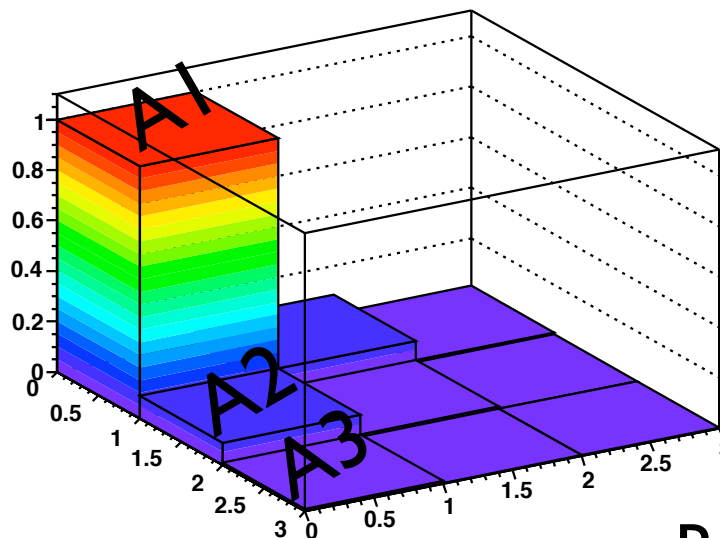


Distribution of the crosstalk

Continuous



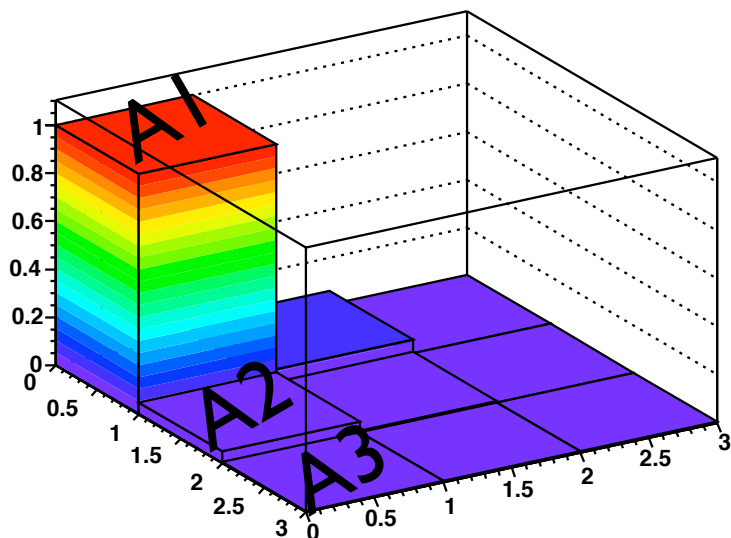
1cm



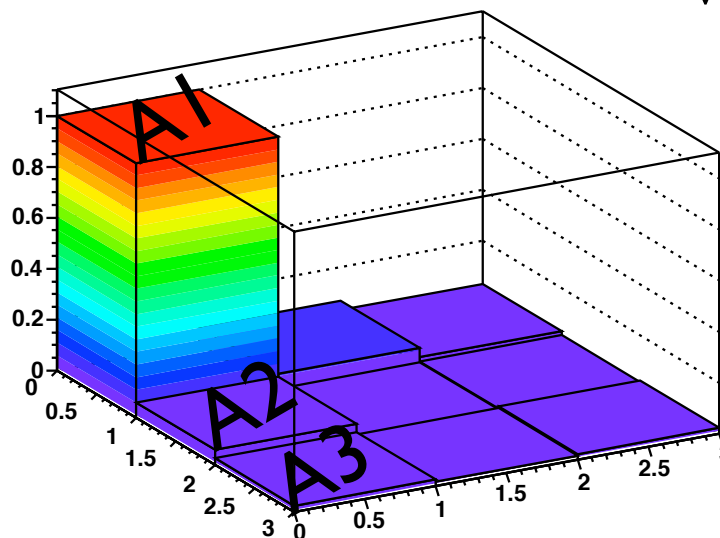
probeheads

$f = 400 \text{ kHz}$

3mm



1cm + Continuous



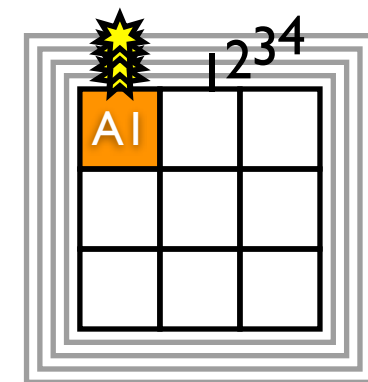
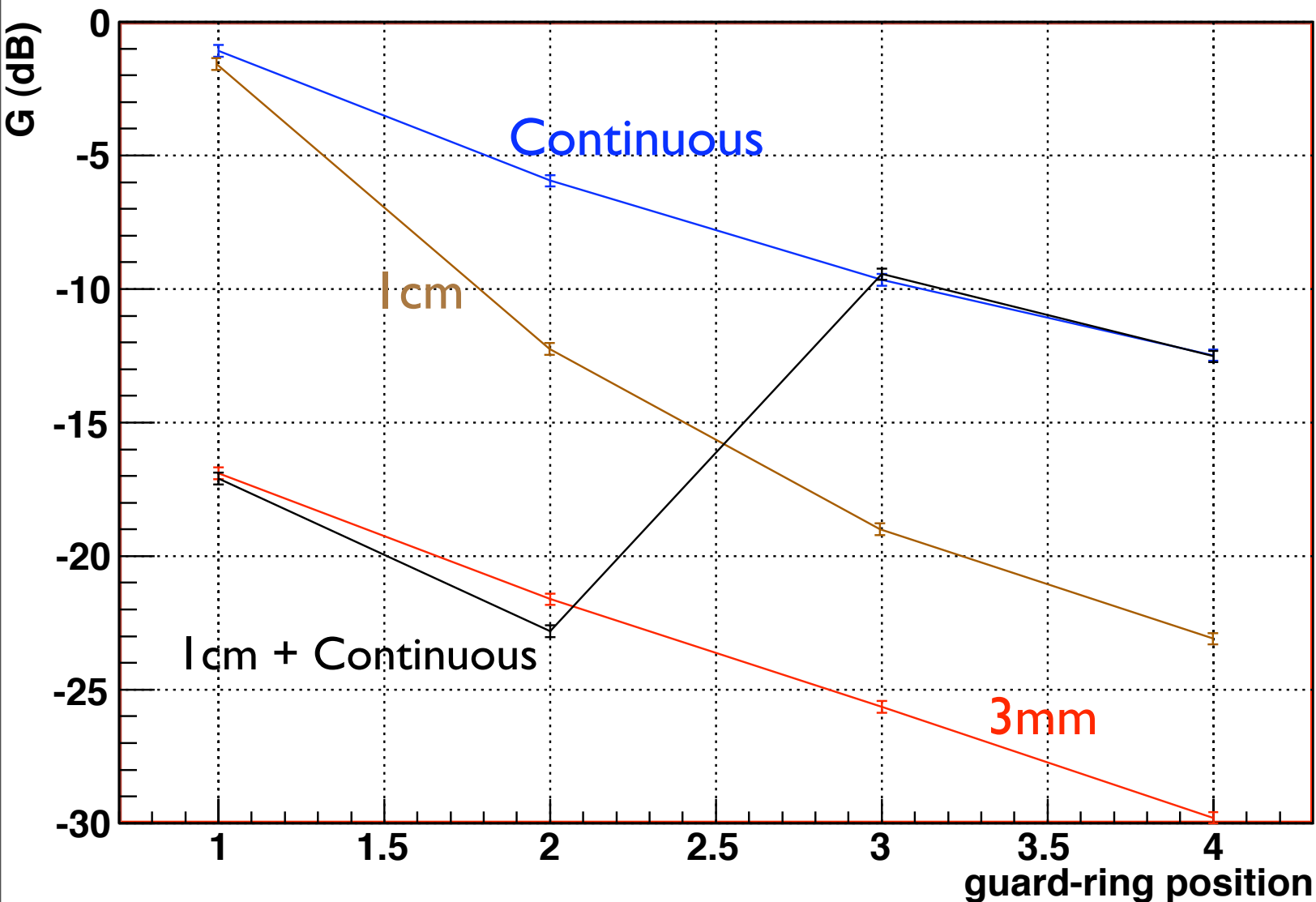
Relative Weights
weight of A1 = 1



Impact of the guard-ring position

A1 f=400 kHz

probeheads





Conclusion

3mm segmented guard-rings induce the lowest crosstalk.

It is the best guard-ring option for preventing from square events.

The measurement method has been validated.
The test bench is calibrated.

This study is just the first step, real 3x3 wafers will be measured *as soon as we'll get them...*

